Record Nr. UNINA9910785903303321 Adhesion aspects in MEMS-NEMS / / edited by S. H. Kim, M. T. Dugger **Titolo** and K. L. Mittal Pubbl/distr/stampa Leiden;; Boston:,: Brill Biggleswade:,: Extenza Turpin [distributor],, 2010 **ISBN** 0-429-08792-6 1-61583-947-X 90-04-19095-3 Descrizione fisica 1 online resource (424 p.) Altri autori (Persone) KimSeong H DuggerMichael T MittalK. L. <1945-> Disciplina 621.381 Soggetti Microelectromechanical systems Nanoelectromechanical systems Adhesion Surfaces (Technology) Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia Note generali Description based upon print version of record. Nota di bibliografia Includes bibliographical references. pt. 1. Understanding through continuum theory -- pt. 2. Computer Nota di contenuto simulation of interfaces -- pt. 3. Adhesion and friction measurements -- pt. 4. Adhesion in practical applications -- pt. 5. Adhesion mitigation strategies. Sommario/riassunto Phenomena associated with the adhesion interaction of surfaces have been a critical aspect of micro- and nanosystem development and performance since the first MicroElectroMechanicalSystems(MEMS) were fabricated. These phenomena are ubiquitous in nature and are present in all systems, however MEMS devices are particularly sensitive to their effects owing to their small size and limited actuation force that can be generated. Extension of MEMS technology concepts to the nanoscale and development of NanoElectroMechanicalSystems(NEMS) will result in

systems even more strongly influenced by surface